

**The Most Widely Used Film Thickness Measurement System
in the World Now Offers Enhanced Flexibility and Ease of Operation
- at an Astonishingly Low Price**

NanoSpec[®]/AFT 2100

*Small Spot Semi-Automatic Film Thickness Measurement System
for Patterned or Monitor Wafers*



- Simple and powerful
- Small spot for patterned wafer sites
- Film thickness from 100Å to 50 microns
- Multi-layer measurements
- Patented absolute reflectance measurement
- Refractive index
- Inexpensive
- Easy to use
- Rugged construction
- High reliability over many years of use
- Auto wafer handling option
- SECS II interface included
- Any size or shape of substrate including magnetic media, wafers, glass, etc.
- Strong customer support